

FIG. 1: Taxonomy of Design Based Yield Improvements

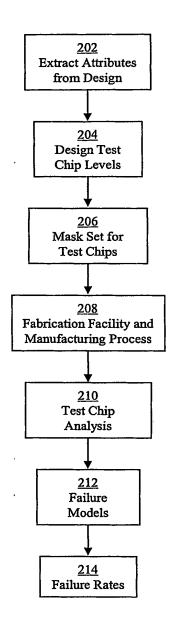


FIG. 2: Determining "Existing Failure Models"

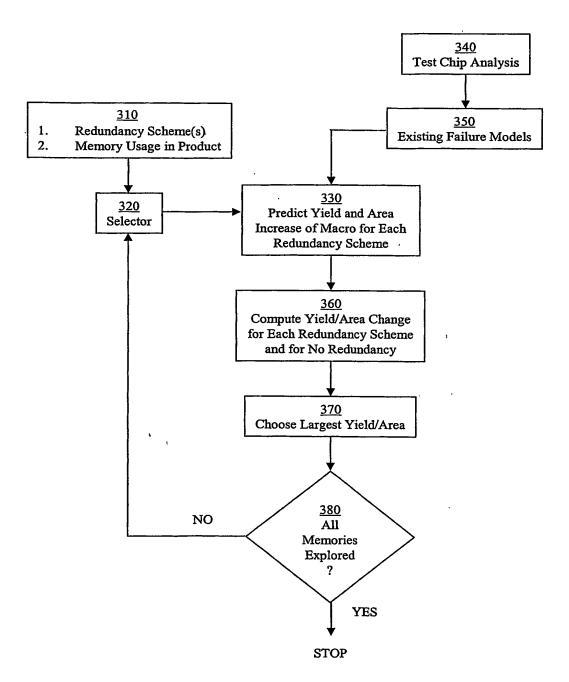


FIG. 3: Bit-Cell Optimization

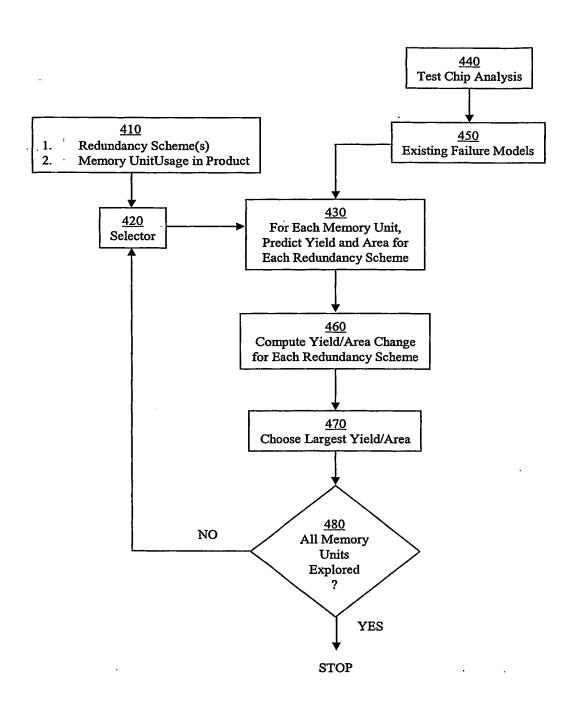


FIG. 4: Redundancy Optimization

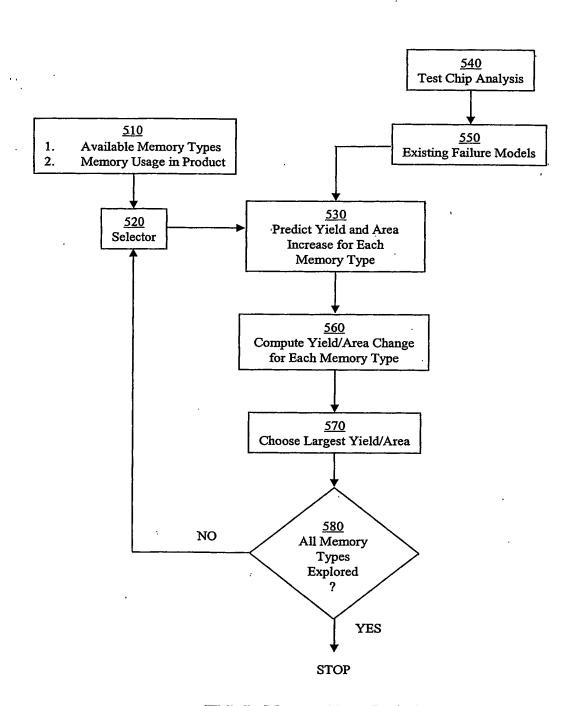


FIG. 5: Memory Type Optimization

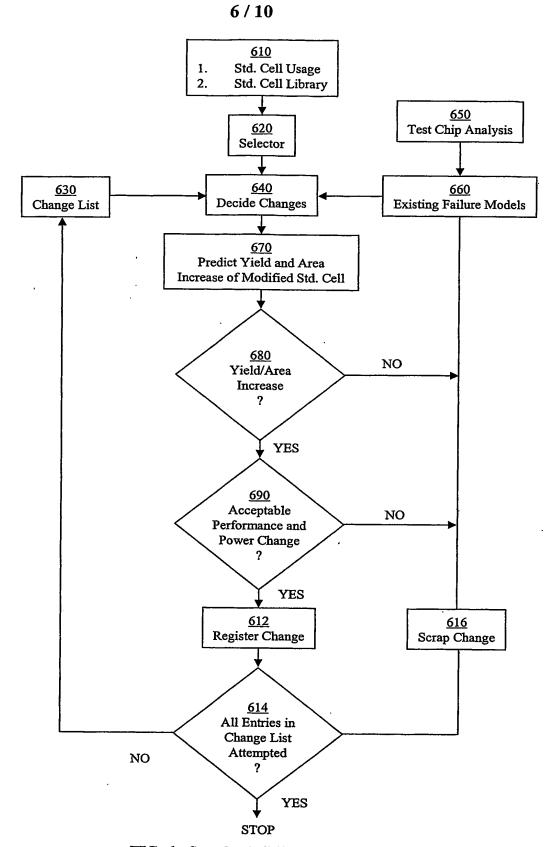


FIG. 6: Standard Cell Optimization

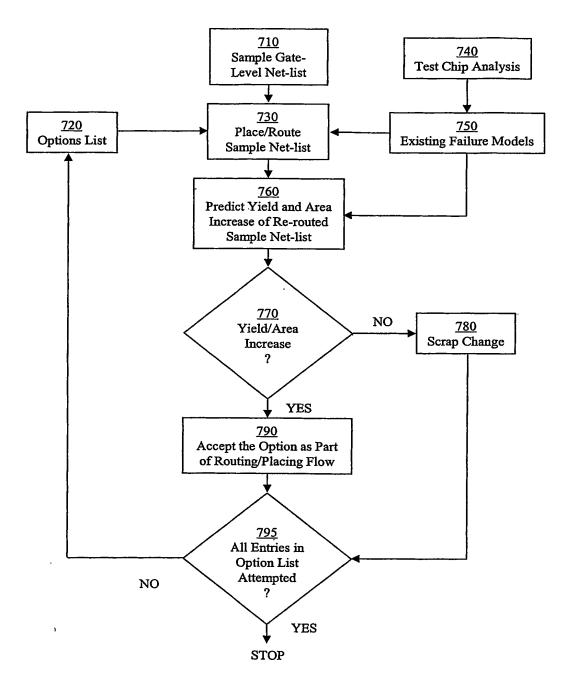


FIG. 7: Router Optimization

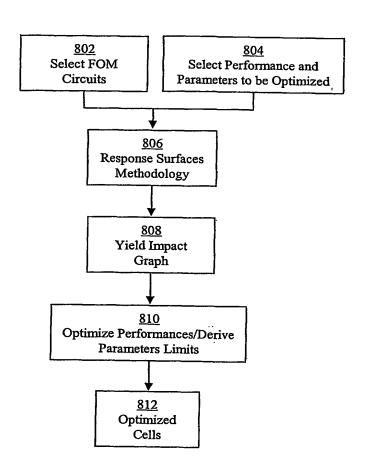


FIG. 8: Parametric Yield Optimization

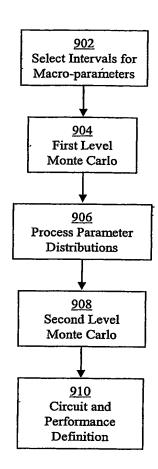


FIG. 9: Yield Impact Graph

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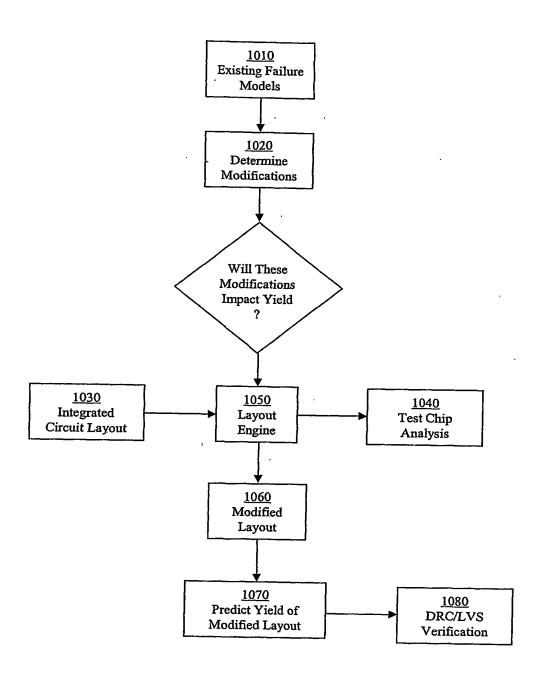


FIG. 10: Post-tape-out Modification